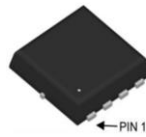
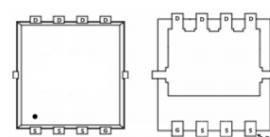
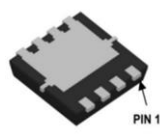


## Main Product Characteristics:

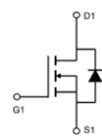
$V_{DSS}$	40V
$R_{DS(on)}$	6.9m $\Omega$ (typ.)
$I_D$	68A



PDFN 3\*3-8L



Pin Assignments



Schematic Diagram

## Main Features

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



## Description

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

## Absolute Rating

Symbol	Parameter	Max.	Units
$I_D$ @ TC = 25°C	Continuous Drain Current, $V_{GS}$ @ 10V ①	68	A
$I_{DM}$	Pulsed Drain Current ②	125	
$P_D$ @ TC = 25°C	Power Dissipation ③	4.16	W
$E_{AS}$	Single Pulse Avalanche Energy @ L=0.1mH	31	mJ
$V_{DS}$	Drain-Source Voltage	40	V
$V_{GS}$	Gate-to-Source Voltage	± 20	V
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C

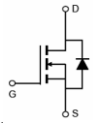
## Thermal Resistance

Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-case ③	—	30	$^{\circ}\text{C/W}$
$R_{\theta JA}$	Junction-to-ambient ( $t \leq 10\text{s}$ ) ④	—	85	$^{\circ}\text{C/W}$

## Electrical Characteristics @ $T_A=25^{\circ}\text{C}$ unless otherwise specified

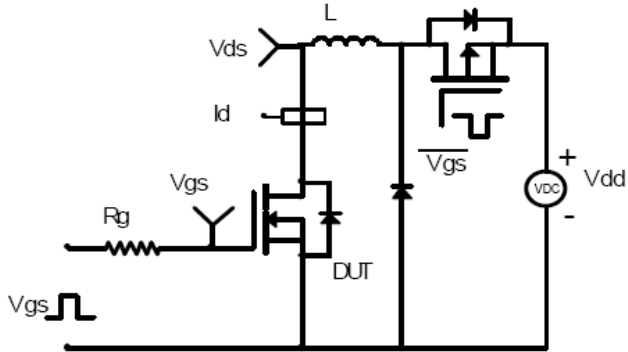
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	40	—	—	V	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	6.9	8.5	$\text{m}\Omega$	$V_{GS}=10\text{V}, I_D=12\text{A}$
		—	10.5	15		$V_{GS}=4.5\text{V}, I_D=10\text{A}$
$V_{GS(th)}$	Gate threshold voltage	1.2	—	2.5	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
$I_{DSS}$	Drain-to-Source leakage current	—	—	1	$\mu\text{A}$	$V_{DS}=32\text{V}, V_{GS} = 0\text{V}$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 20\text{V}$
		—	—	-100		$V_{GS} = -20\text{V}$
$Q_g$	Total gate charge	—	5.8	—	nC	$I_D = 12\text{A},$ $V_{DS}=20\text{V},$ $V_{GS} = 4.5\text{V}$
$Q_{gs}$	Gate-to-Source charge	—	3	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	1.2	—		
$t_{d(on)}$	Turn-on delay time	—	14.3	—	ns	$V_{DD}=15\text{V}, V_{DS}=10\text{V},$ $R_{GEN}=3.3\Omega$ $I_D = 1\text{A}$
$t_r$	Rise time	—	5.6	—		
$t_{d(off)}$	Turn-Off delay time	—	20	—		
$t_f$	Fall time	—	11	—		
$C_{iss}$	Input capacitance	—	690	—	pF	$V_{GS} = 0\text{V}$ $V_{DS} = 15\text{V}$ $f = 1\text{MHz}$
$C_{oss}$	Output capacitance	—	193	—		
$C_{rss}$	Reverse transfer capacitance	—	38	—		

## Source-Drain Ratings and Characteristics

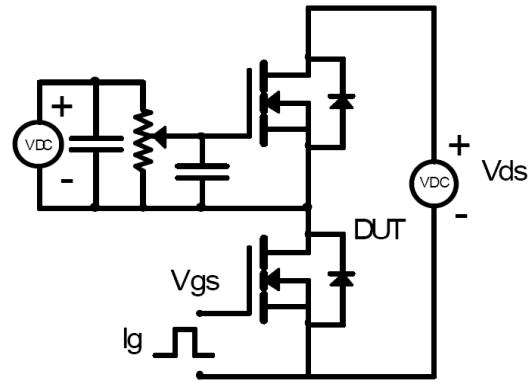
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	30	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$V_{SD}$	Diode Forward Voltage	—	—	1	V	$I_S=1\text{A}, V_{GS}=0\text{V}$

## Test circuits and Waveforms

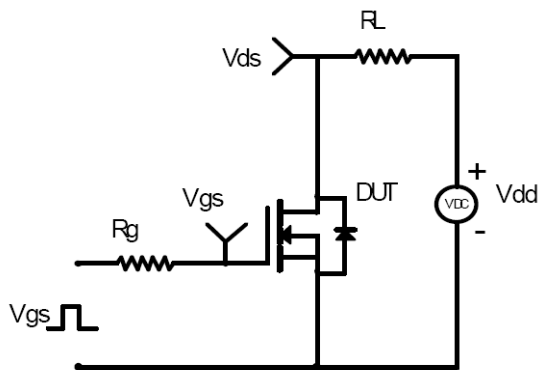
**EAS Test Circuit:**



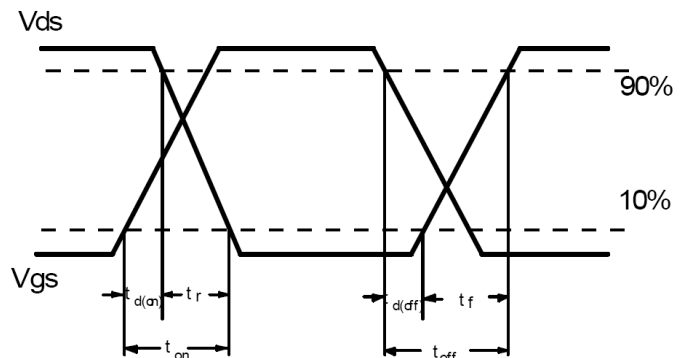
**Gate charge test circuit:**



**Switching Time Test Circuit:**



**Switching Waveforms:**



## Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

## Typical Electrical and Thermal Characteristics

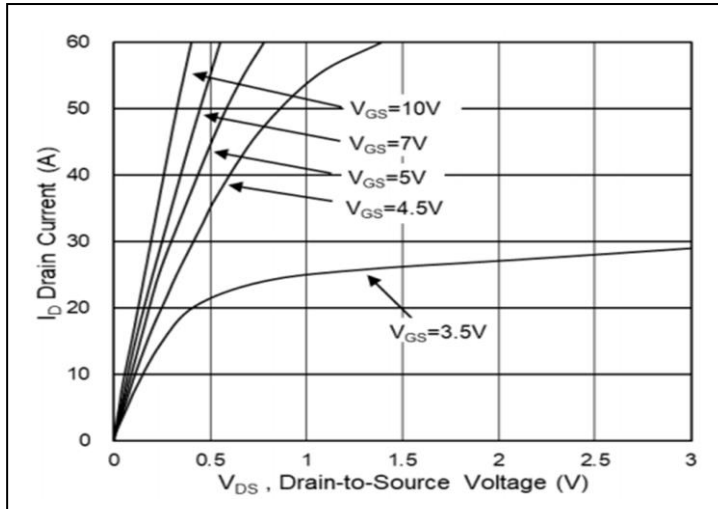


Figure 1. Typ. Output Characteristics

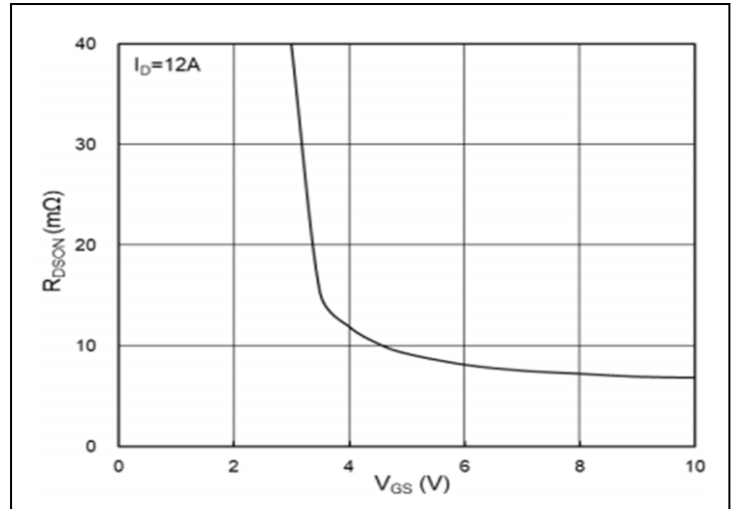


Figure 2. On-Resistance vs. G-S Voltage

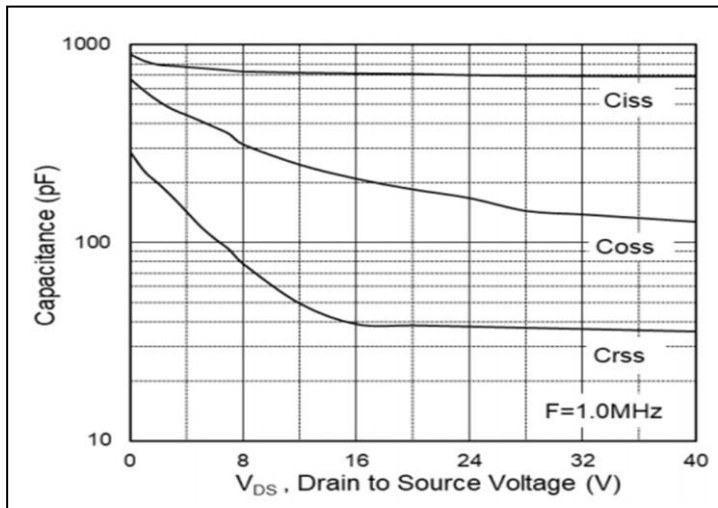


Figure 3. Typ. Capacitance

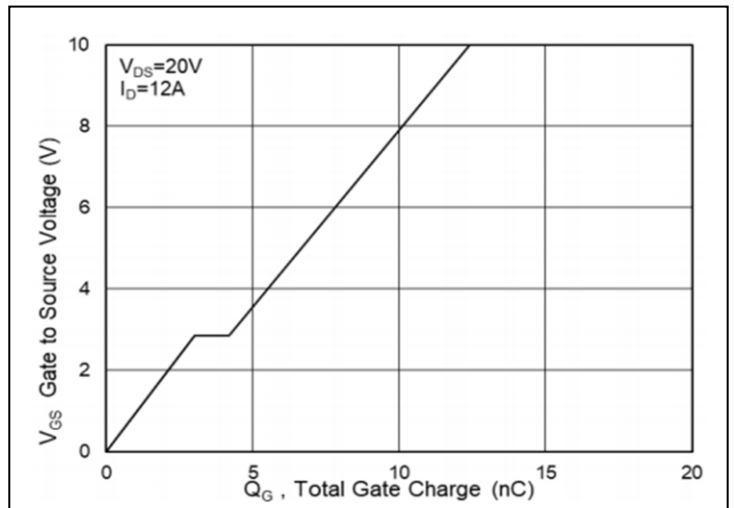


Figure 4. Typ. Gate Charge

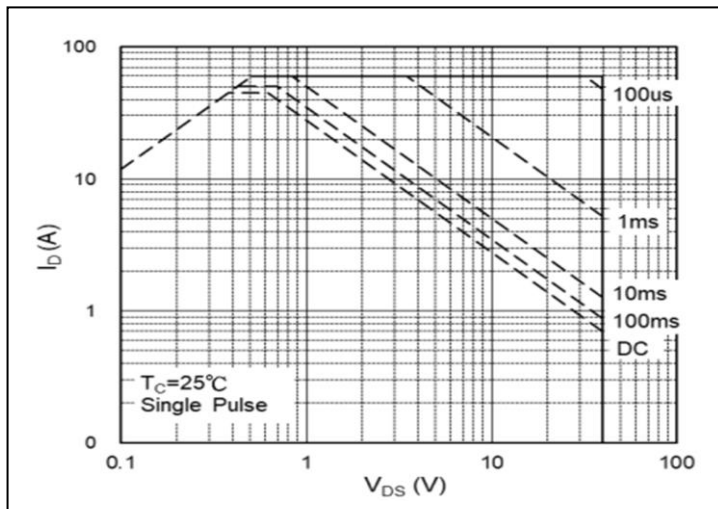


Figure 5. Safe Operation Area  $T_C = 25^\circ C$

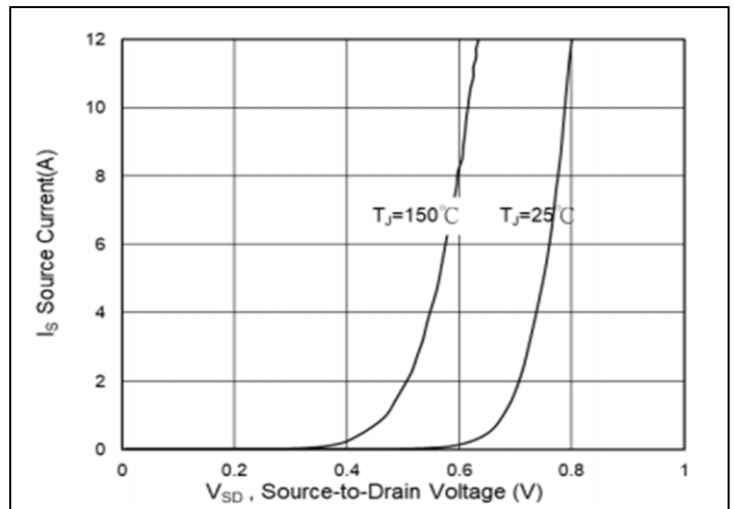


Figure 6. Source Drain Forward Characteristics

## Typical Electrical and Thermal Characteristics

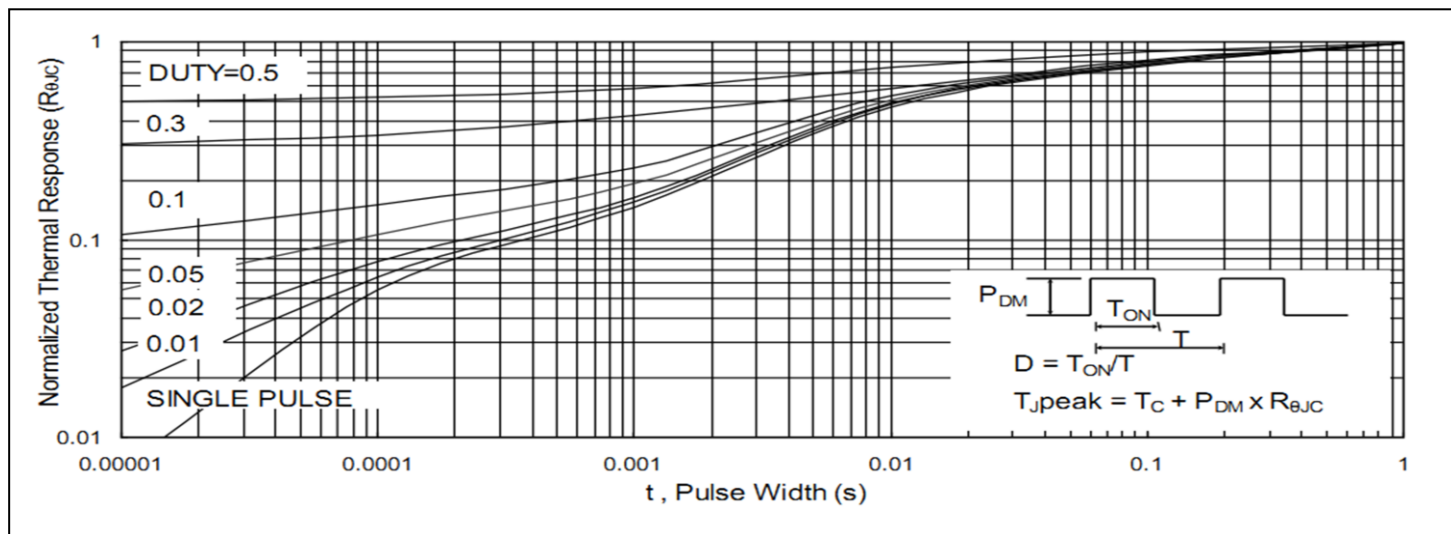
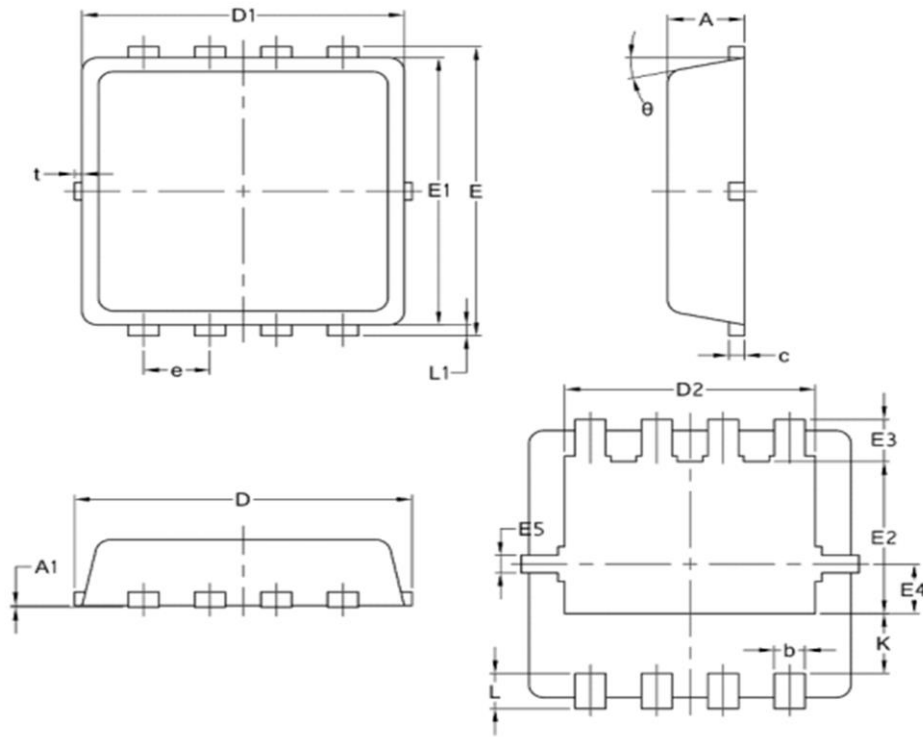


Figure 7. Max. Transient Thermal Impedance

**Mechanical Data:**


Symbol	Common		
	mm		
	Mim	Nom	Max
A	0.70	0.75	0.85
A1	/	/	0.05
b	0.20	0.30	0.40
c	0.10	0.152	0.25
D	3.15	3.30	3.45
D1	3.00	3.15	3.25
D2	2.29	2.45	2.65
E	3.15	3.30	3.45
E1	2.90	3.05	3.20
E2	1.54	1.74	1.94
E3	0.28	0.48	0.65
E4	0.37	0.57	0.77
E5	0.10	0.20	0.30
e	0.60	0.65	0.70
K	0.59	0.69	0.89
L	0.30	0.40	0.50
L1	0.06	0.125	0.20
t	0	0.075	0.13
Φ	10	12	14

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